BUK7905-40AIE

N-channel TrenchPLUS standard level FET

Rev. 05 — 10 February 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. The devices include TrenchPLUS current sensing and diodes for ElectroStatic Discharge (ESD) protection. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Electrostatically robust due to integrated protection diodes
- Low conduction losses due to low on-state resistance
- Q101 compliant

- Reduced component count due to integrated current sensor
- Suitable for standard level gate drive sources

1.3 Applications

Electrical Power Assisted Steering (EPAS) Variable Valve Timing for engines

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	-	40	V
I_D	drain current	V_{GS} = 10 V; T_{mb} = 25 °C; see <u>Figure 2</u> ; see <u>Figure 3</u> ;	<u>[1]</u>	-	-	155	Α
Static ch	aracteristics						
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 50 A; T_j = 25 °C; see <u>Figure 7</u> ; see <u>Figure 8</u>		-	4.5	5	mΩ
I _D /I _{sense}	ratio of drain current to sense current	$T_j > -55 ^{\circ}\text{C}; T_j < 175 ^{\circ}\text{C};$ $V_{GS} > 10 ^{\circ}\text{V}$		450	500	550	

^[1] Current is limited by power dissipation chip rating.



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		d
2	ISENSE	Sense current	mb	, i
3	D	drain		
4	KS	Kelvin source		
5	S	source		9 \ \ \ \ \ \ \ \ \
mb	D	mounting base; connected to drain	1 2 3 4 5	MBL368 Isense Kelvin source
			SOT263B (TO-220)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7905-40AIE	TO-220	plastic single-ended package; heatsink mounted; 1 mounting hole; 5-lead TO-220	SOT263B

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

		3 7 1 1				
Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	40	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	40	V
V_{GS}	gate-source voltage			-20	20	V
I _D	drain current	T _{mb} = 25 °C; V _{GS} = 10 V; see <u>Figure 2</u> ; see <u>Figure 3</u>	[1]	-	155	Α
				-	75	Α
		T _{mb} = 100 °C; V _{GS} = 10 V; see <u>Figure 2</u>	[2]	-	75	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; $t_p \le 10 \mu s$; pulsed; see Figure 3		-	620	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 1</u>		-	272	W
I _{GS(CL)} gate-source clamping		continuous		-	10	mA
	current	pulsed; $t_p = 5$ ms; $\delta = 0.01$		-	50	mΑ
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dra	ain diode					
Is	source current	$T_{mb} = 25 ^{\circ}C$	[1]	-	155	Α
			[2]	-	75	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	620	Α
Avalance r	uggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 75 A; $V_{sup} \le 40$ V; R_{GS} = 50 Ω ; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	1.46	J
Electrostat	ic discharge					
V _{esd}	electrostatic discharge voltage	HBM; C = 100 pF; R = 1.5 kΩ		-	6	kV

^[1] Current is limited by power dissipation chip rating.

^[2] Continuous current is limited by package.

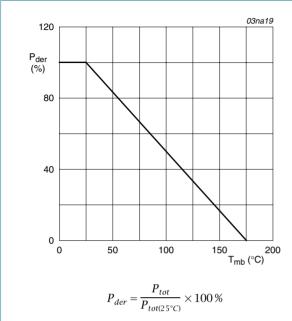


Fig 1. Normalized total power dissipation as a function of mounting base temperature

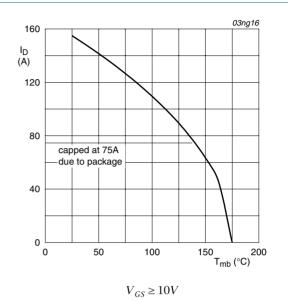
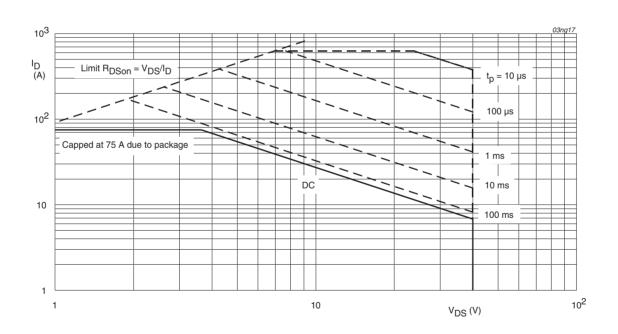


Fig 2. Continuous drain current as a function of mounting base temperature



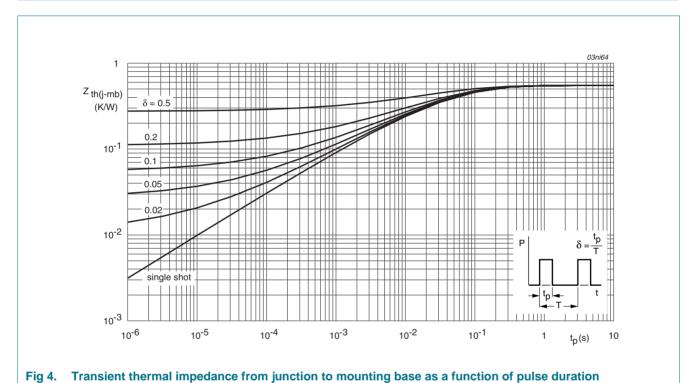
 $T_{mb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 4	-	-	0.55	K/W



6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	cteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	40	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	36	-	-	V
V _{GS(th)} gate-source threshold voltage		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 25 \text{ °C}$; see Figure 9	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see Figure 9	1	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 9	-	-	4.4	V
I _{DSS}	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.1	10	μΑ
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	250	μΑ
$V_{(BR)GSS}$	gate-source breakdown voltage	$I_G = 1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j < 175 °C;$ $T_j > -55 °C$	20	22	-	V
		$I_G = -1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j < 175 °C;$ $T_j > -55 °C$	20	22	-	V
lgss	gate leakage current	V _{DS} = 0 V; V _{GS} = 10 V; T _j = 25 °C	-	22	1000	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 25 \text{ °C}$	-	22	1000	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 175 \text{ °C}$	-	-	10	μΑ
		V _{DS} = 0 V; V _{GS} = -10 V; T _j = 175 °C	-	-	10	μΑ
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 7; see Figure 8	-	4.5	5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 7; see Figure 8	-	-	9.5	mΩ
R _{(D-ISENSE)on}	drain-ISENSE on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 100 \text{ mA}; T_j = 25 \text{ °C};$ see Figure 16	0.98	1.08	1.18	Ω
		$V_{GS} = 10 \text{ V}; I_D = 100 \text{ mA}; T_j = 175 \text{ °C};$ see Figure 16	1.86	2.05	2.24	Ω
I _D /I _{sense}	ratio of drain current to sense current	$V_{GS} > 10 \text{ V; } T_j > -55 \text{ °C; } T_j < 175 \text{ °C}$	450	500	550	
Dynamic ch	aracteristics					
$Q_{G(tot)}$	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	120	127	nC
Q_{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 14</u>	-	19	22	nC
Q_{GD}	gate-drain charge		-	50	60	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	4300	5000	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	1400	1670	pF
C _{rss}	reverse transfer capacitance		-	820	1100	pF
d(on)	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	35	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	115	-	ns
t _{d(off)}	turn-off delay time		-	155	-	ns
t _f	fall time		-	110	-	ns

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
L _D	internal drain inductance	from upper edge of drain mounting base to centre of die; $T_j = 25$ °C	-	2.5	-	nΗ
L _S	internal source inductance	from source lead to source bond pad; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ
Source-dra	ain diode					
V_{SD}	source-drain voltage	$I_S = 40 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 17	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = -10 \text{ V}$;	-	96	-	ns
Q _r	recovered charge	$V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$	-	224	-	nC

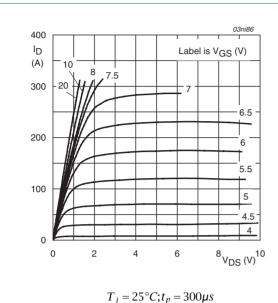


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

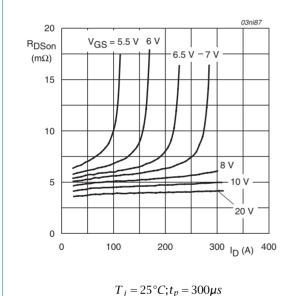
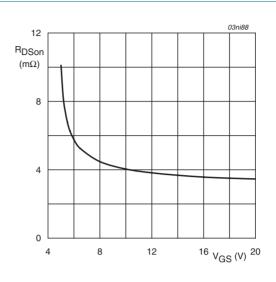
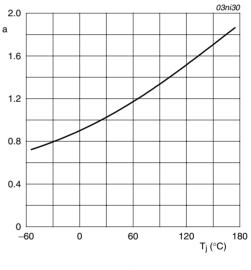


Fig 7. Drain-source on-state resistance as a function of drain current; typical values



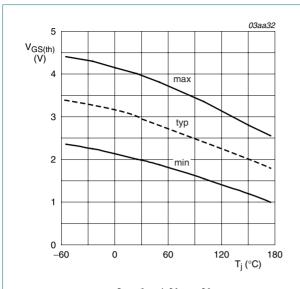
 $T_j = 25^{\circ}C; I_D = 50A$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



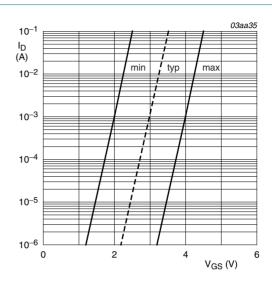
 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



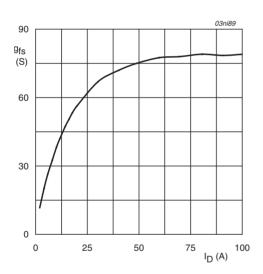
 $I_D=1\, mA; V_{DS}=V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



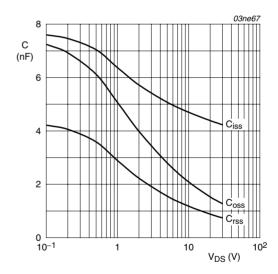
$$T_{j} = 25 \,^{\circ}C; V_{DS} = 5V$$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



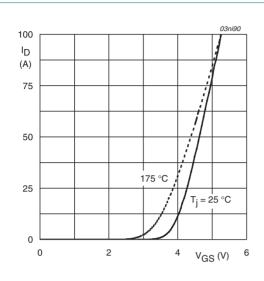
 $T_i = 25^{\circ}C; V_{DS} = 25V$

Fig 11. Forward transconductance as a function of drain current; typical values



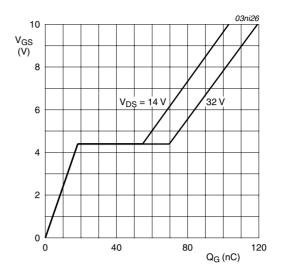
$$V_{GS} = 0V; f = 1MHz$$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $V_{DS} = 25V$

Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values



$$T_j = 25^{\circ}C; I_D = 25A$$

Fig 14. Gate-source voltage as a function of turn-on gate charge; typical values

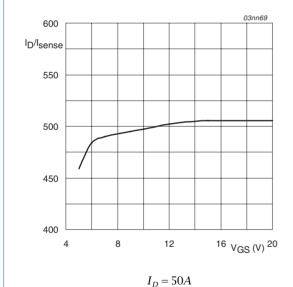
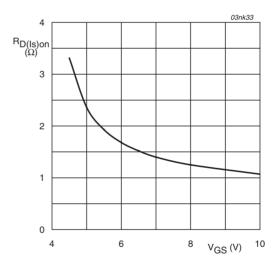
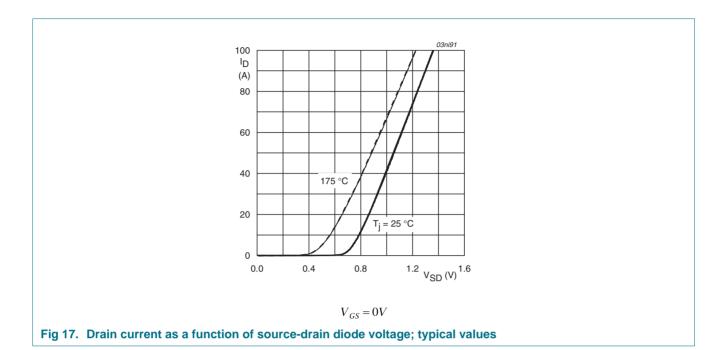


Fig 15. Drain-sense current ratio as a function of gate-source voltage; typical values



 $I_{sense} = 25mA$

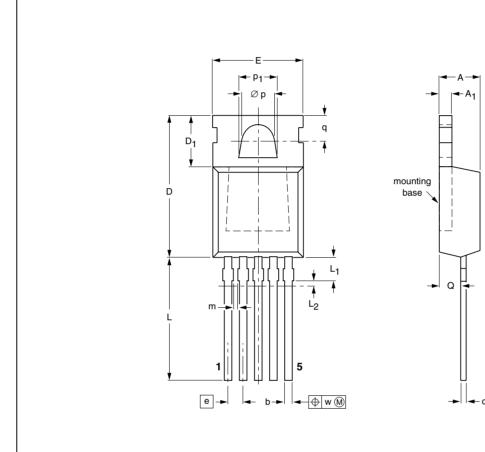
Fig 16. Drain-sense current on-state resistance as a function of gate-source voltage; typical values



7. Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 5-lead TO-220

SOT263B



0 5 10 mm

DIMENSIONS (mm are the original dimensions)

UNIT	A	A ₁	b	С	D	D ₁	E	е	L	L ₁ ⁽¹⁾	L ₂ ⁽²⁾	m	∅p	P ₁	q	Q	w
mm	4.5 4.1	1.39 1.27	0.85 0.70	0.7 0.4	15.8 15.2	6.4 5.9	10.3 9.7	1.7	15.0 13.5	2.4 1.6	0.5	0.8 0.6	3.8 3.6	4.3 4.1	3.0 2.7	2.6 2.2	0.4

Notes

- 1. Terminal dimensions are uncontrolled in this zone.
- 2. Positional accuracy of the terminals is controlled in this zone.

OUTLINE			REFER	EUROPEAN	ISSUE DATE			
	VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
	SOT263B		5-lead TO-220				01-01-11	

Fig 18. Package outline SOT263B (TO-220)

8. Revision history

Table 7. Revision history

	-			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7905-40AIE_5	20090210	Product data sheet	-	BUK71_7905_40AIE-04
Modifications:		of this data sheet has bee of NXP Semiconductors.	n redesigned to comply w	rith the new identity
	 Legal texts 	have been adapted to the	new company name whe	re appropriate.
	 Type numb 	er BUK7905-40AIE separa	ited from data sheet BUK	71_7905_40AIE-04.
BUK71_7905_40AIE-04	20040206	Product data	-	BUK71_7905_40AIE-03
BUK71_7905_40AIE-03	20030523	Product data	-	BUK71_7905_40AIE-02
BUK71_7905_40AIE-02	20021001	Product data	-	BUK71_7905_40AIE-01
BUK71_7905_40AIE-01	20020725	Product data	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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10. Contact information

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BUK7905-40AIE

N-channel TrenchPLUS standard level FET

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